Silicon Carbide Schottky Diode

1200 V, 40 A

Description

Silicon Carbide (SiC) Schottky Diodes use a completely new technology that provides superior switching performance and higher reliability compared to Silicon. No reverse recovery current, temperature dependent switching characteristics, and excellent thermal performance sets Silicon Carbide as the next generation of power semiconductor. System benefits include highest efficiency, faster operation frequency, increased power density, reduced EMI, and reduced system size and cost.

Features

- Max Junction Temperature 175°C
- Avalanche Rated 420 mJ
- High Surge Current Capacity
- Positive Temperature Coefficient
- Ease of Paralleling
- No Reverse Recovery/No Forward Recovery

Applications

- General Purpose
- SMPS, Solar Inverter, UPS
- Power Switching Circuits

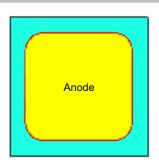
Die Information

- Wafer Diameter: 6 inch
- Die Size: 4,200 × 4,200 µm (include Scribe Lane)
- Metallization:
 - Top Ti/TiN/AlCu 4 μm
 - ◆ Back Ti/NiV/Ag
- Die Thickness: Typ. 200 μm
- Bonding Pad Size
 - Anode 3,620 × 3,620 μm
- Recommended Wire Bond (Note 1)
 - Anode: $20 \text{ mil} \times 3$



ON Semiconductor®

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ORDERING INFORMATION

See detailed ordering and shipping information on page 3 of this data sheet.

ELECTRICAL CHARACTERISTICS ON WAFER (NOTE 2) ($T_C = 25^{\circ}C$ unless otherwise noted) (Note 2)

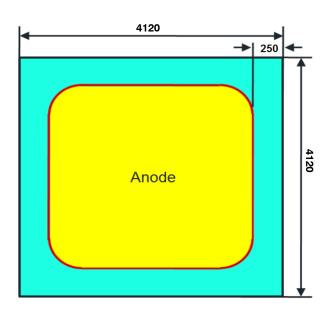
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
V _R	Reverse Blocking Voltage	$I_R = 200 \mu A, T_C = 25^{\circ}C$	1200	-	-	V
V _F	Forward Voltage	$I_F = 40 \text{ A}, T_C = 25^{\circ}\text{C}$	1.20	-	1.75	V
I _R	Reverse Current	V _R = 1200 V, T _C = 25°C	-	ı	200	μΑ

NOTES

- 1. Based on TO-247 package of ON Semiconductor.
- 2. Tested 100% on wafer.

Die Layout (Dimension: μm, except Scribe Lane)

Cross Section



N+ Substrate

Cathode

Figure 1. Die Layout

Figure 2. Cross Section

Passivation Information

Passivation Material: Polymide (PSPI)
Passivation Type: Local Passivation
Passivation Thickness: 90 KA

The Configuration of Chips (Based on 6" Wafer)

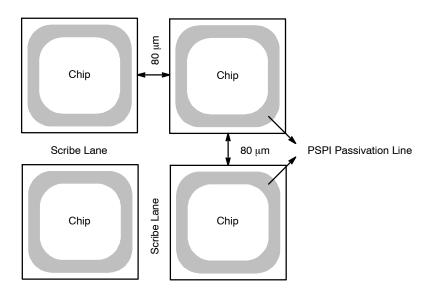


Figure 3. Saw-on-film Frame Packing Based on Tested Wafer

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit		
V_{RRM}	Peak Repetitive Reverse Voltage	uk Repetitive Reverse Voltage		V	
E _{AS}	Single Pulse Avalanche Energy	(Note 3)	420	mJ	
I _F	Continuous Rectified Forward Current @ T _C <	Continuous Rectified Forward Current @ T _C < 155°C			
	Continuous Rectified Forward Current @ T _C <	135°C	61		
I _{F, Max}	Non-Repetitive Peak Forward Surge Current	T _C = 25°C, 10 μs	1650	Α	
		T _C = 150°C, 10 μs	1550	Α	
I _{F,SM}	Non-Repetitive Forward Surge Current	Half-Sine Pulse, t _p = 8.3 ms	270	Α	
I _{F,RM}	Repetitive Forward Surge Current	Half-Sine Pulse, t _p = 8.3 ms	120	А	
Ptot	Power Dissipation	T _C = 25°C	682	W	
		T _C = 150°C	114	W	
T _J , T _{STG}	Operating and Storage Temperature Range	•	-55 to +175	°C	
	TO247 Mounting Torque, M3 Screw		60	Ncm	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

3. E_{AS} of 420 mJ is based on starting T_J = 25°C, L = 0.5 mH, I_{AS} = 41 A, V = 50 V.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ hetaJC}$	Thermal Resistance, Junction to Case, Max	0.22	°C/W

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
V_{F}	Forward Voltage	I _F = 40 A, T _C = 25°C	-	1.45	1.75	V
		I _F = 40 A, T _C = 125°C	-	1.7	2.0	
		I _F = 40 A, T _C = 175°C	-	2.0	2.4	
I _R	Reverse Current	V _R = 1200 V, T _C = 25°C	-	-	200	μΑ
		V _R = 1200 V, T _C = 125°C	-	-	300	
		V _R = 1200 V, T _C = 175°C	-	-	400	
Q_{C}	Total Capacitive Charge	V = 800 V	-	220	=	nC
С	Total Capacitance	V _R = 1 V, f = 100 kHz	-	2250	-	pF
		V _R = 400 V, f = 100 kHz	-	204	-	
		V _R = 800 V, f = 100 kHz	-	169	-	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
FFSH40120A	FFSH40120A	TO-247-2LD (Halogen Free)	30 Units / Tube

TYPICAL CHARACTERISTICS

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

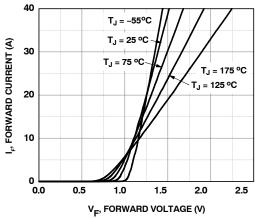


Figure 4. Forward Characteristics

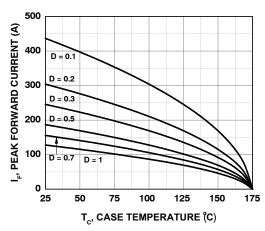


Figure 6. Current Derating

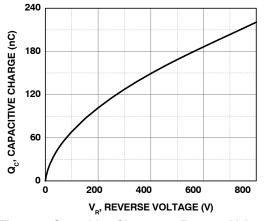


Figure 8. Capacitive Charge vs. Reverse Voltage

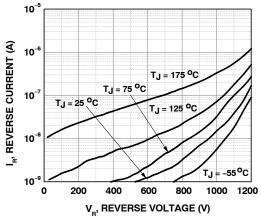


Figure 5. Reverse Characteristics

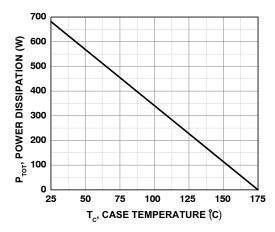


Figure 7. Power Derating

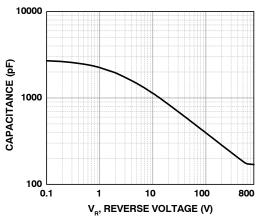


Figure 9. Capacitance vs. Reverse Voltage

TYPICAL CHARACTERISTICS

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

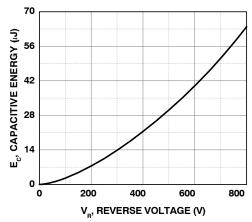


Figure 10. Capacitance Stored Energy

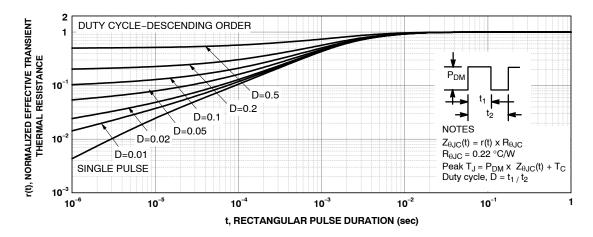


Figure 11. Junction-to-Case Transient Thermal Response Curve

TEST CIRCUIT AND WAVEFORMS

L = 0.5 mH $R < 0.1 \Omega$ $V_{DD} = 50 \text{ V}$ $EAVL = 1/2LI2 \left[V_{R(AVL)} / \left(V_{R(AVL)} - V_{DD} \right) \right]$ $Q1 = IGBT \left(BV_{CES} > DUT V_{R(AVL)} \right)$ V_{AVL} CURRENT SENSE V_{DD} DUT V_{DD} V_{DD} V_{DD} V_{DD} V_{DD} V_{DD}

Figure 12. Unclamped Inductive Switching Test Circuit & Waveform

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